



APPLICATION DATA SHEET

Electronic Version v14

Stylesheet Version v14.0

Title of Invention	INCREASE PRODUCTIVITY AT WAFER TEST USING PROBE RETEST DATA ANALYSIS		
Application Type : regular, utility			
Attorney Docket Number : BUR920040137US1			
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as my attorney(s) or agent(s) to prosecute the application identified above, and to transact all business in the United States Patent and Trademark Office connected therewith.			

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